

Details regarding VLAC-007 site

Accreditation No.	VLAC - 007
Laboratory Name	Hitachi Information& Communication Engineering Ltd.
Test Site name	Nakai EMC Test Site
Address	456, Sakai, Nakai-machi, Ashigarakami-gun, Kanagawa, 259-0157 Japan
Responsible person	Ryoutaro Hoshi
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- SCOPE OF ACCREDITATION -

【Measurement Method】

Emission Test

Radiated disturbance: Enclosure Port

Radiated field strength measurement (CISPR 16-2-3, ANSI C63.4:2003)

(Test Condition) On the ground reference plane, Measurement distance: 3m, 10m

Quasi Free Space, Frequency Range (1GHz ~ 6GHz)

(Test Facilities) Nakai EMC Test Site No.1, No.2 and No.3

(Test Condition) Radiated magnetic field strength measurement (CISPR16-2-3)

Loop Antenna

(Test Facilities) Nakai EMC Test Site No.1, No.2 and No.3

Conducted disturbance: AC/DC mains port

Disturbance voltage measurement (CISPR 16-2-1, ANSI C63.4:2003)

(Test Condition) AMN (CISPR 16-1-2)

(Test Facilities) Nakai EMC Test Site No.1, N0.1 Shielded room, No.2 and No.3

Conducted disturbance: Telecommunications port

Disturbance voltage measurement (CISPR 22 Clause 9.6 and Annex C)

(Test Condition) AAN (CISPR 16-1-2)

Disturbance current measurement (CISPR 22 Clause 9.6 and Annex C)

(Test Condition) Current probe (CISPR 16-1-2)

(Test Facilities) Nakai EMC Test Site No.1, N0.1 Shielded room, No.2 and No.3

Immunity Test

ESD (IEC61000-4-2),

Radiated electromagnetic field strength (IEC61000-4-3),

EFT/B (IEC61000-4-4): AC mains port/Telecommunications port,

Surge (IEC61000-4-5): AC mains port/Telecommunications port,

RF conducted (IEC61000-4-6): AC mains port/Telecommunications port,

Power frequency magnetic field (IEC61000-4-8),

Interruptions and voltage variations/dip (IEC61000-4-11)

(Test Facilities) Nakai EMC Test Site No.1, No.1 Shielded room, No.2 and No.3

Except Radiated and conducted Immunity test for Nakai EMC Test Site No.1 Shielded room

Harmonic Test in Public Low Voltage Systems

Harmonic current (IEC61000-3-2), Voltage fluctuations and flicker (IEC61000-3-3)

(Test Facilities) Nakai EMC Test Site No.1, No.1 Shielded room, No.2 and No.3

Telecommunications Equipment Performance Test 2

Magnetic Field Measurement

[Test Facilities] Nakai EMC Test Site No.1, No.1 Shielded room, No.2 and No.3

【Measurement Standard】

Emission Test

V-3 : VCCI Technical Requirement

FCC 47CFR/Part15 Subpart B & Subpart C/ANSI C63.4 (2003/2009)

CISPR 11, CISPR 22, CISPR 25, EN 55011, EN 55022, EN 55025, J 55011, J 55022,

Technical requirement of Electrical Appliances and Material Safety Act

for the disturbance noise level: Clause 1 of Ministerial Ordinance (Chapter 4 and 5)

AS/NZS CISPR 11, AS/NZS CISPR 22, ICES-003

IEC 61000-6-3, IEC 61000-6-4, EN 61000-6-3, EN 61000-6-4

AS/NZS 61000.6.3, AS/NZS 61000.6.4

IEC60601-1-2(Particular requirement IEC60601-2 series),

EN60601-1-2((Particular requirement EN60601-2 series)

JIS T0601-1-2(Particular requirement JIS T0601-2 series)

IEC61326-1(Particular requirement IEC61326-2 series),

EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1

Immunity Test

CISPR 24, EN 55024, AS/NZS CISPR 24

IEC 61000-6-1, IEC 61000-6-2, EN 61000-6-1, EN 61000-6-2

JIS C 61000-6-1, JIS C 61000-6-2

AS/NZS 61000.6.1, AS/NZS 61000.6.2

IEC60601-1-2(Particular requirement IEC60601-2 series),

EN60601-1-2((Particular requirement EN60601-2 series)

JIS T0601-1-2(Particular requirement JIS T0601-2 series)

IEC61326-1(Particular requirement IEC61326-2 series),

EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1

Harmonic Test in Public Low Voltage Systems

IEC 61000-3-2, JIS C 61000-3-2, EN 61000-3-2, IEC 61000-3-3, EN 61000-3-3

IEC 61000-3-12, EN 61000-3-12

IEC60601-1-2(Particular requirement IEC60601-2 series),

EN60601-1-2((Particular requirement EN60601-2 series)

JIS T0601-1-2(Particular requirement JIS T0601-2 series)

IEC61326-1(Particular requirement IEC61326-2 series),

EN61326-1(Particular requirement EN61326-2 series), JIS C1806-1

Telecommunications Equipment Performance Test 2

IEC 62233, EN 50366